Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	2	"6714902"	US-PGPUB; USPAT; EPO; DERWENT	OR	OFF	2005/07/20 13:20
L2	15	("4527249" | "4722071" | "4924430" | "5095454" | "5191541" | "5355321" | "5600787" | "5648909" | "5657239" | "5805459" | "5946475" | "6026222" | "6086626" | "6097884" | "6286126").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/07/20 14:00
L3	768	feedback near cycle	US-PGPUB; USPAT; EPO; DERWENT	OR	OFF	2005/07/20 14:00
L4	547	L3 and @ad<"20010901"	US-PGPUB; USPAT; EPO; DERWENT	OR	OFF	2005/07/20 14:03
L5	0	L4 and 7%%/$.ccls.	US-PGPUB; USPAT; EPO; DERWENT	OR	OFF	2005/07/20 14:02
L6	513	L3 and @ad<"20010901"	US-PGPUB; USPAT	OR	OFF	2005/07/20 14:03
L7	153	L6 and sensiti$6	US-PGPUB; USPAT	OR	OFF	2005/07/20 14:06
L8	720	714/738.ccls.	US-PGPUB; USPAT; EPO; DERWENT	OR	OFF	2005/07/20 14:08
L9	604	L8 and @ad<"20010901"	US-PGPUB; USPAT; EPO; DERWENT	OR	OFF	2005/07/20 14:09
L10	427	L9 and (cycl$2 or loop$1 or feedback or sequential)	US-PGPUB; USPAT; EPO; DERWENT	OR	OFF	2005/07/20 14:10
L13	8	"5910958"	USPAT	OR	OFF	2005/07/20 15:14
L14	7	("5910958").URPN.	USPAT	OR	OFF	2005/07/20 15:23
L15	35	(boolean adj satisfiability) and @ad<"20010901"	USPAT	OR	OFF	2005/07/20 15:23

Results for "(larrabee<in>au) <and> (test pattern generation<in>ti)"

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IEEE CNF	IEEE Conference Proceeding
IEE CNF	IEE Conference Proceeding
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1. **Test pattern generation using Boolean satisfiability**
Larrabee, T.;
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Digital Object Identified 10.1109/43.108614
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2. **A framework for evaluating test pattern generation strategies**
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Results for "(boolean satisfiability<and>cyclic) <and> (pyr >= 1951 <and> pyr <= 2001)"
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IEE JNL	IEE Journal or Magazine
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